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*IGBT* 

# SGH30N60RUF

# **Short Circuit Rated IGBT**

# **General Description**

Fairchild's RUF series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUF series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

## **Features**

- Short circuit rated 10us @  $T_C = 100$ °C,  $V_{GE} = 15V$
- · High speed switching
- Low saturation voltage :  $V_{CE(sat)} = 2.2 \text{ V}$  @  $I_C = 30 \text{A}$
- · High input impedance

# **Applications**

AC & DC motor controls, general purpose inverters, robotics, and servo controls.





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Description		SGH30N60RUF	Units
V <sub>CES</sub>	Collector-Emitter Voltage		600	V
V <sub>GES</sub>	Gate-Emitter Voltage		± 20	V
_	Collector Current	@ T <sub>C</sub> = 25°C	48	Α
I <sub>C</sub>	Collector Current	@ T <sub>C</sub> = 100°C	30	Α
I <sub>CM (1)</sub>	Pulsed Collector Current		90	Α
	Short Circuit Withstand Time	@ T <sub>C</sub> =100°C	10	us
T <sub>SC</sub>	Maximum Power Dissipation	@ T <sub>C</sub> = 25°C	235	W
	Maximum Power Dissipation	@ T <sub>C</sub> = 100°C	90	W
TJ	Operating Junction Temperature		-55 to +150	°C
T <sub>stg</sub>	Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temp. for Soldering Purposes, 1/8" from Case for 5 Seconds		300	°C

#### Notes

(1) Repetitive rating : Pulse width limited by max. junction temperature

# **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.53	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Cha	racteristics					
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250uA$	600			V
ΔB <sub>VCES</sub> / ΔΤ <sub>J</sub>	Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0V$ , $I_C = 1mA$		0.6		V/°C
I <sub>CES</sub>	Collector Cut-Off Current	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0V			250	uA
I <sub>GES</sub>	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Cha	racteristics					
V <sub>GE(th)</sub>	G-E Threshold Voltage	$I_C = 30$ mA, $V_{CE} = V_{GE}$	5.0	6.0	8.5	V
GE(tn)	Collector to Emitter	$I_C = 30A$ , $V_{GF} = 15V$		2.2	2.8	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 48A$ , $V_{GE} = 15V$		2.5		V
D.mami	, ,	10 1013, 1GE 101				
C <sub>ies</sub>	c Characteristics Input Capacitance			1970		pF
C <sub>oes</sub>	Output Capacitance	$V_{CE} = 30V, V_{GE} = 0V,$		310		pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz		74		pF
t <sub>d(on)</sub>	Turn-On Delay Time			30		ns
_ ` '	Rise Time	-		65		
t <sub>r</sub>	Turn-Off Delay Time	.,		54	80	ns
t <sub>d(off)</sub>	Fall Time	$V_{CC} = 300 \text{ V}, I_{C} = 30\text{A},$		138	200	ns
t <sub>f</sub>	**	$R_G = 7\Omega$ , $V_{GE} = 15V$ , Inductive Load, $T_C = 25^{\circ}C$		919	200	ns
E <sub>on</sub>	Turn-On Switching Loss	inductive Load, 1 <sub>C</sub> = 25 G		814		uJ
E <sub>off</sub>	Turn-Off Switching Loss	-		_		uJ
E <sub>ts</sub>	Total Switching Loss			1733	2430	uJ
t <sub>d(on)</sub> ₊	Turn-On Delay Time	-		34 67		ns
t <sub>r</sub>	Rise Time	.,				ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 30\text{A},$		60	90	ns
t <sub>f</sub>	Fall Time	$R_G = 7\Omega$ , $V_{GE} = 15V$ , Inductive Load, $T_C = 125$ °C		281	400	ns
E <sub>on</sub>	Turn-On Switching Loss	inductive Load, T <sub>C</sub> = 125 C		921		uJ
E <sub>off</sub>	Turn-Off Switching Loss	-		1556		uJ
E <sub>ts</sub>	Total Switching Loss	V 200 V V 45V		2477	3470	uJ
T <sub>sc</sub>	Short Circuit Withstand Time	V <sub>CC</sub> = 300 V, V <sub>GE</sub> = 15V @ T <sub>C</sub> = 100°C	10			us
_	Total Gate Charge	.,		85	120	nC
	Total State Straings					
Q <sub>ge</sub>	Gate-Emitter Charge	$V_{CE} = 300 \text{ V}, I_{C} = 30\text{A},$		17	25	nC
Q <sub>g</sub> Q <sub>ge</sub> Q <sub>gc</sub>	· · · · · · · · · · · · · · · · · · ·	$V_{CE} = 300 \text{ V}, I_{C} = 30\text{A},$ $V_{GE} = 15\text{V}$		17 39	25 55	nC nC

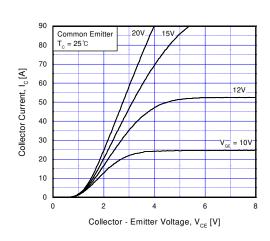


Fig 1. Typical Output Characteristics

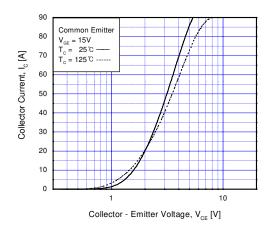


Fig 2. Typical Saturation Voltage Characteristics

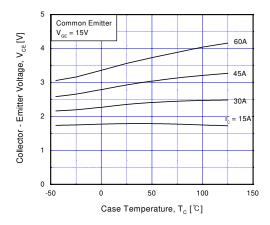


Fig 3. Saturation Voltage vs. Case Temperature at Variant Current Level

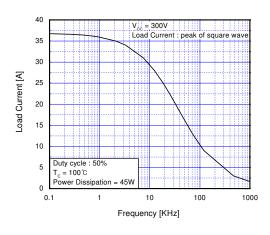


Fig 4. Load Current vs. Frequency

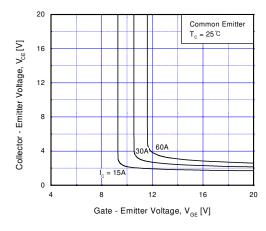


Fig 5. Saturation Voltage vs.  $V_{\text{GE}}$ 

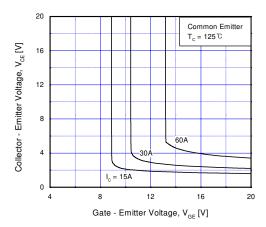
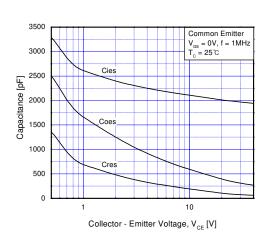


Fig 6. Saturation Voltage vs.  $V_{\rm GE}$ 

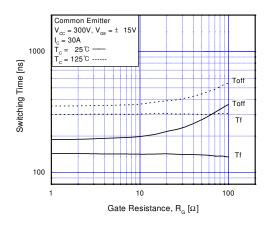
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Common Emitter  $V_{CC} = 300V, V_{GE} = \pm 15V$   $I_{CC} = 300$   $I_{CC} = 25^{\circ}C$   $I_{CC} = 125^{\circ}C$   $I_{$ 

Fig 7. Capacitance Characteristics

Fig 8. Turn-On Characteristics vs. Gate Resistance



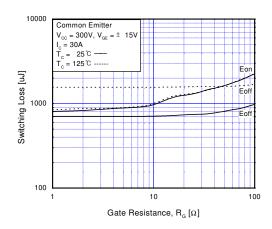
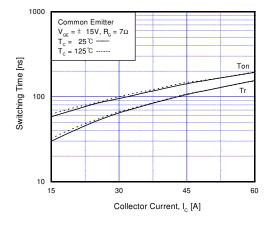


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

Fig 10. Switching Loss vs. Gate Resistance



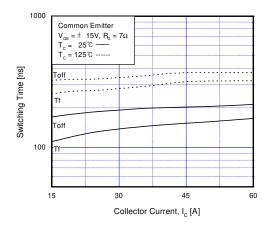
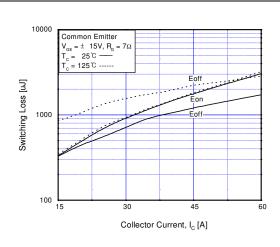


Fig 11. Turn-On Characteristics vs. Collector Current

Fig 12. Turn-Off Characteristics vs. Collector Current



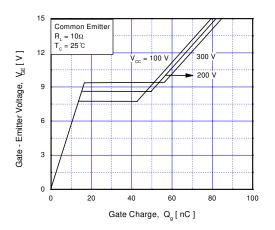
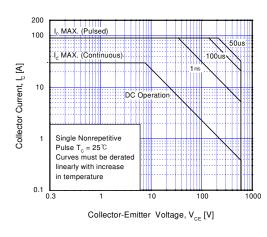


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



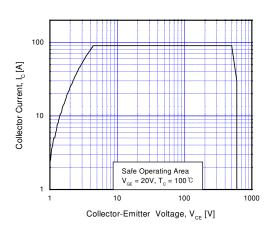


Fig 15. SOA Characteristics

Fig 16. Turn-Off SOA Characteristics

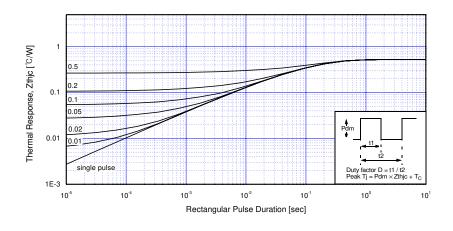
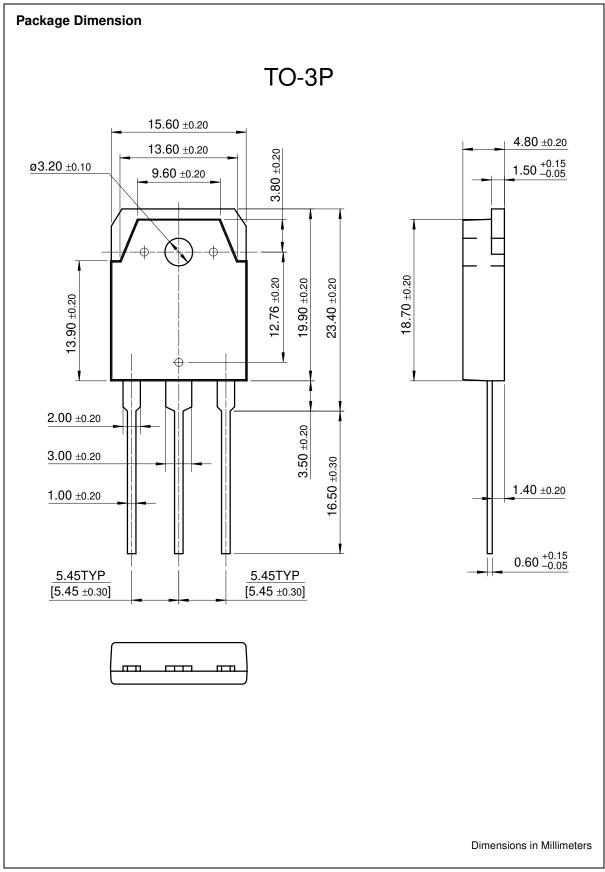


Fig 17. Transient Thermal Impedance of IGBT



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